

Data Sheet- EddyCus® TF map 2525SR

P_T_2525_14



Highlights

- ▶ Contact-free imaging
- ▶ High resolution imaging (25 to 1,000,000 points)
- ▶ Defect imaging
- ▶ Mapping of encapsulated layers

Parameters

- ▶ Sheet resistance (Ohm/sq)
- ▶ Metal layer thickness (nm, μm)
- ▶ Metal substrate thickness (μm)
- ▶ Anisotropy
- ▶ Defects
- ▶ Integrity assessment

Applications

- ▶ Architectural glass (LowE)
- ▶ Touch screens and flat monitors
- ▶ OLED and LED applications
- ▶ Smart-glass applications
- ▶ Transparent antistatic foils
- ▶ Photovoltaics
- ▶ Semiconductors
- ▶ De-icing and heating applications
- ▶ Batteries and fuel cells
- ▶ Packaging materials

Materials

- ▶ Metal films and meshes
- ▶ Conductive oxides
- ▶ Nanowire films
- ▶ Graphene, CNT, Graphite
- ▶ Printed films
- ▶ Conductive polymers (PEDOT:PSS)
- ▶ Other conductive films and materials

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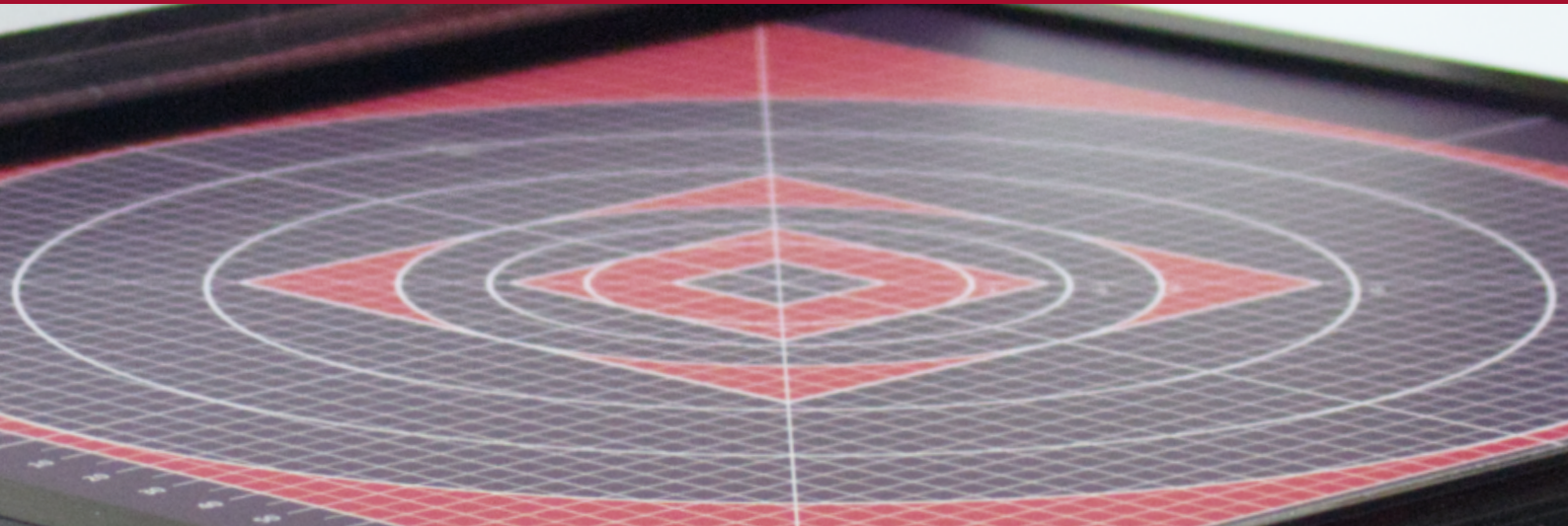
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Made and Engineered in Germany

Innovation Award by
Free State of Saxony 2013
1st Place





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| Measurement technology | Non-contact eddy current sensor |
| Substrates | E.g. Foils, glass, wafer, etc. |
| Max. Scanning area | 10 inch / 254 mm x 254 mm (larger on request) |
| Edge effect correction / exclusion | 2 mm edge exclusion for standard sizes |
| Max. Sample thickness / sensor gap | 2 / 5 / 10 / 25 mm (defined by the thickest sample) |
| Sheet resistance range | 0.0001 – 10 Ohm/sq; 2 to 7 % accuracy |
| accuracy can be optimized over sheet resistance decade within a customer specified range | 0.01 – 10 Ohm/sq; 2 to 3 % accuracy 10 – 100 Ohm/sq; 2 to 7 % accuracy |
| Thickness measurement of metal films (e.g. Aluminum, Copper) | 2 nm - 2 mm (in accordance with sheet resistance) |
| Scanning Pitch | 1 / 2 / 5 / 10 mm (other on request) |
| Measurement points per time (square shape) | 10,000 measurement points in 5 minutes 1,000,000 measurement points in 30 minutes |
| Scanning time | 4 inch / 100 mm x 100 mm in 0.5 to 5 minutes (1-10mm pitch) 8 inch / 200 mm x 200 mm in 1.5 to 15 minutes (1-10mm pitch) |
| Device dimension (w/h/d) / weight | 23.6" x 9.05" x 31.5" / 549 mm x 236 mm x 786(836) mm / 27 kg |
| Available features | Metal thickness imaging Anisotropy sheet resistance sensor |

Software and Handling - Sheet Resistance Analyzer 2.0

